Searcn Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/826,784	LAI ET AL.	
Examiner	Art Unit	
Raymond Phan	2111	

	SEAR	CHED	
Class	Subclass	Date	Examiner
710	260-269, 48-51	4/20/2005	RP

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
710	260,262	4/25/2005	RP
710	268	4/25/2005	RP

(INCLUDING SEARCH STRATEGY)		
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